

## TC74LVQ02F/FN/FS

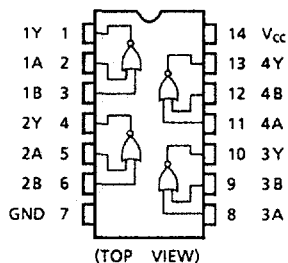
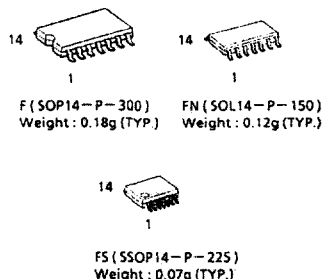
### Quad 2-Input NOR Gate

The TC74LVQ02 is a high speed CMOS 2-INPUT NOR GATE fabricated with silicon gate and double-layer metal wiring C<sup>2</sup>MOS technology.

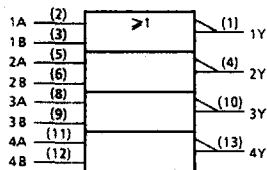
Designed for use in 3.3 Volt systems, it achieves high speed operation while maintaining the CMOS low power dissipation. The internal circuit is composed of 3 stages including buffer output, which provide high noise immunity and stable output. All inputs are equipped with protection circuits against static discharge or transient excess voltage.

### Features

- High Speed:  $t_{pd} = 3.4ns$  (Typ.) at  $V_{CC} = 3.3V$
- Low Power Dissipation:  $I_{CC} = 2.5\mu A$  (Max.) at  $T_a = 25^\circ C$
- Input Voltage Level:
  - $V_{IL} = 0.8V$  (Max.) at  $V_{CC} = 3V$
  - $V_{IH} = 2.0V$  (Min.) at  $V_{CC} = 3V$
- Symmetrical Output Impedance:  $|I_{OH}| = |I_{OL}| = 12mA$  (Min.)
- Balanced Propagation Delays:  $t_{pLH} \approx t_{pHL}$
- Pin and Function Compatible with 74HC02



Pin Assignment



IEC Logic Symbol

Truth Table

Inputs		Outputs
A	B	Y
L	L	H
L	H	L
H	L	L
H	H	L

## Absolute Maximum Ratings

Parameter	Symbol	Value	Unit
Supply Voltage Range	$V_{CC}$	-0.5 - 7.0	V
DC Input Voltage	$V_{IN}$	-0.5 - $V_{CC} + 0.5$	V
DC Output Voltage	$V_{OUT}$	-0.5 - $V_{CC} + 0.5$	V
Input Diode Current	$I_{IK}$	$\pm 20$	mA
Output Diode Current	$I_{OK}$	$\pm 50$	mA
DC Output Current	$I_{OUT}$	$\pm 50$	mA
DC $V_{CC}$ /Ground Current	$I_{CC}$	$\pm 100$	mA
Power Dissipation	$P_D$	180	mW
Storage Temperature	$T_{stg}$	-65 - 150	°C
Lead Temperature 10sec	$T_L$	300	°C

## Recommended Operating Conditions

Parameter	Symbol	Value	Unit
Supply Voltage	$V_{CC}$	2.0 - 3.6	V
Input Voltage	$V_{IN}$	0 - $V_{CC}$	V
Output Voltage	$V_{OUT}$	0 - $V_{CC}$	V
Operating Temperature	$T_{opr}$	-40 - 85	°C
Input Rise and Fall Time	$dt/dv$	0 - 100	ns/V

## DC Electrical Characteristics

Parameter	Symbol	Test Condition	$T_a = 25^\circ\text{C}$				$T_a = -40 \sim 85^\circ\text{C}$		Unit
			$V_{CC}$ (V)	Min	Typ.	Max.	Min.	Max.	
High-Level Input Voltage	$V_{IH}$		3.0	2.0	-	-	2.0	-	V
Low-Level Input Voltage	$V_{IL}$		3.0	-	-	0.8	-	0.8	
High-Level Output Voltage	$V_{OH}$	$V_{IN} = V_{IL}$ $I_{OH} = -50\mu\text{A}$ $I_{OH} = -12\text{mA}$	3.0	2.9	3.0	-	2.9	-	
			3.0	2.58	-	-	2.48	-	
Low-Level Output Voltage	$V_{OL}$	$V_{IN} = V_{IH}$ $V_{IN} = V_{IL}$ $I_{OL} = 50\mu\text{A}$ $I_{OL} = 12\text{mA}$	3.0	-	0.0	0.1	-	0.1	
			3.0	-	-	0.36	-	0.44	
Input Leakage Current	$I_{IN}$	$V_{IN} = V_{CC}$ or GND	3.6	-	-	$\pm 0.1$	-	$\pm 1.0$	$\mu\text{A}$
Quiescent Supply Current	$I_{CC}$	$V_{IN} = V_{CC}$ or GND	3.6	-	-	2.5	-	25.0	

**AC Electrical Characteristics (Input  $t_r = t_f = 3\text{ns}$ ,  $C_L = 50\text{pF}$ ,  $R_L = 500\Omega$ )**

Parameter	Symbol	Test Condition	V <sub>CC</sub> (V)	Ta = 25°C			Ta = -40 ~ 85°C		Unit
				Min	Typ.	Max.	Min.	Max.	
Propagation Delay Time	t <sub>pLH</sub> t <sub>pHL</sub>		2.7 3.3±0.3	—	5.2 4.3	10.6 7.5	1.0 1.0	12.0 8.0	ns
Output to Output Skew	t <sub>osLH</sub> t <sub>osHL</sub>	(Note 1)	2.7 3.3±0.3	—	—	1.5 1.5	—	1.5 1.5	
Input Capacitance	C <sub>IN</sub>	(Note 2)		—	5	10	—	10	pF
Power Dissipation Capacitance	C <sub>PD</sub>	(Note 3)		—	26	—	—	—	

Note (1) Parameter guaranteed by design.  $t_{osLH} = |t_{pLHm} - t_{pLHn}|$ ,  $t_{osHL} = |t_{pHLm} - t_{pHLn}|$

Note (2) Parameter guaranteed by design.

Note (3) C<sub>PD</sub> is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption.

Average operating current can be obtained by the equation:

$$I_{CC}(\text{opr}) = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}/4 \text{ (per Gate)}$$

**Noise Characteristics (Input  $t_r = t_f = 3\text{ns}$ ,  $C_L = 50\text{pF}$ ,  $R_L = 500\Omega$ )**

Parameter	Symbol	Test Condition	V <sub>CC</sub>	Ta = 25°C		Unit
				Typ.	Max.	
Quiet Output Maximum Dynamic V <sub>OLP</sub>	V <sub>OLP</sub>		3.3	0.3	0.8	V
Quiet Output Minimum Dynamic V <sub>OL</sub>	V <sub>OLV</sub>		3.3	-0.3	-0.8	V
Minimum High Level Dynamic Input Voltage	V <sub>IHD</sub>		3.3	—	2.0	V
Maximum High Level Dynamic Input Voltage	V <sub>ILD</sub>		3.3	—	0.8	V



## Notes

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